

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/798,075	<b>Applicant(s)/Patent under Reexamination</b> CHANG, KIL JAE
	<b>Examiner</b> Jared J. Fureman	<b>Art Unit</b> 2876

# SEARCHED

Class	Subclass	Date	Examiner
235	381 18 68	10/25/2005	JJF
194	344 229	10/26/2005	
	205 215		
	225 226		
	232 237		
221	277 2		
	7 206		
	207 265		
	296 289	10/26/2005	JJF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PGPub text search - see search history printout		10/31/2005	JJF